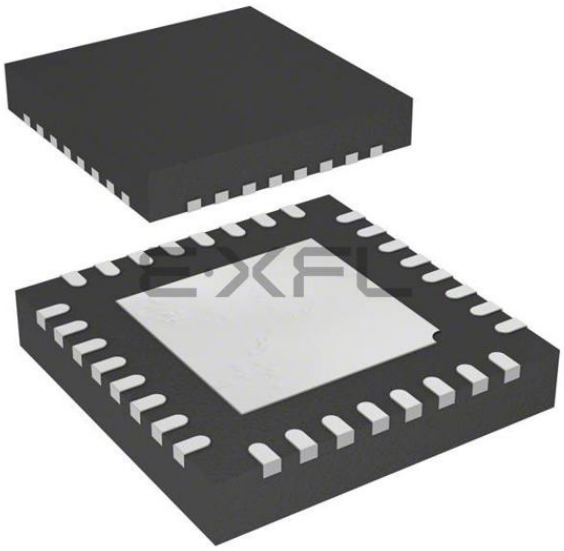

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	28
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	640 x 8
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	2.95V ~ 5.5V
Data Converters	A/D 7x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-UFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8s903k3u3

List of figures

Table 6. STM8S903K3 UFQFPN32/LQFP32/SDIP32 pin descriptions (continued)

SDIP32	LQFP/ UFQFP32	Pin name	Type	Input			Output				Main function (after reset)	Default alternate function	Alternate function after remap [option bit]
				floating	wpu	Ext. interrupt	High sink(1)	Speed	OD	PP			
12	7	PA3/ TIM5_CH3 [SPI_NSS] [UART1_TX]	I/O	**X**	X	X	HS	O3	X	X	**Port A3**	Timer 5 channel 3	SPI master/ slave select [AFR1] /UART1 data transmit [AFR 1:0]
13	8	PF4 [UART1_RX]	I/O	**X**	X	-	-	O1	X	X	**Port F4**	-	UART1 data receive [AFR1:0]
14	9	PB7	I/O	**X**	X	X	-	O1	X	X	**Port B7**	-	-
15	10	PB6	I/O	**X**	X	X	-	O1	X	X	**Port B6**	-	-
16	11	PB5/ I2C_SDA [TIM1_BKIN]	I/O	**X**	-	X	-	O1	T (3)	-	**Port B5**	I2C data	Timer 1 - break input [AFR4]
17	12	PB4/ I2C_SCL [ADC_ETR]	I/O	**X**	-	X	-	O1	T	-	**Port B4**	I2C clock	ADC external trigger [AFR4]
18	13	PB3/ AIN3/TIM1_ETR	I/O	**X**	X	X	HS	O3	X	X	**Port B3**	Analog input 3/ Timer 1 external trigger	-
19	14	PB2/ AIN2/ TIM1_CH3N	I/O	**X**	X	X	HS	O3	X	X	**Port B2**	Analog input 2/ Timer 1 - inverted channel 3	-
20	15	PB1/ AIN1/ TIM1_CH2N	I/O	**X**	X	X	HS	O3	X	X	**Port B1**	Analog input 1/ Timer 1 - inverted channel 2	-
21	16	PB0/ AIN0/ TIM1_CH1N	I/O	**X**	X	X	HS	O3	X	X	**Port B0**	Analog input 0/ Timer 1 - inverted channel 1	-
22	17	PE5/ SPI_NSS [TIM1_CH1N]	I/O	**X**	X	X	HS	O3	X	X	Port E5	SPI master/slave select	Timer 1 - inverted channel 1 [AFR1:0]
23	18	PC1/ TIM1_CH1/ UART1_CK [TIM1_CH2N]	I/O	**X**	X	X	HS	O3	X	X	Port C1	Timer 1 - channel 1 UART1 clock	Timer 1 - inverted channel 2 [AFR1:0]

Table 6. STM8S903K3 UFQFPN32/LQFP32/SDIP32 pin descriptions (continued)

SDIP32	LQFP/ UFQFP32	Pin name	Type	Input			Output				Main function (after reset)	Default alternate function	Alternate function after remap [option bit]
				floating	wpu	Ext. interrupt	High sink(1)	Speed	OD	PP			
24	19	PC2/ TIM1_CH2 [TIM1_CH3N]	I/O	**X**	X	X	HS	O3	X	X	Port C2	Timer 1 - channel 2	Timer 1 - inverted channel 3 [AFR1:0]
25	20	PC3/ TIM1_CH3/TLI/ [TIM1_CH1N]	I/O	**X**	X	X	HS	O3	X	X	Port C3	Timer 1 - channel 3	Top level interrupt [AFR3] Timer 1 inverted channel 1 [AFR7]
26	21	PC4/ TIM1_CH4/ CLK_CCO/AIN2/ [TIM1_CH2N]	I/O	**X**	X	X	HS	O3	X	X	Port C4	Timer 1 - channel 4 /configurable clock output	Analog input 2 [AFR2]Timer 1 inverted channel 2 [AFR7]
27	22	PC5/SPI_SCK [TIM5_CH1]	I/O	**X**	X	X	HS	O3	X	X	Port C5	SPI clock	Timer 5 channel 1 [AFR0]
28	23	PC6/ SPI_MOSI [TIM1_CH1]	I/O	**X**	X	X	HS	O3	X	X	Port C6	SPI master out/slave in	Timer 1 channel 1 [AFR0]
29	24	PC7/ SPI_MISO [TIM1_CH2]	I/O	**X**	X	X	HS	O3	X	X	Port C7	SPI master in/ slave out	Timer 1 channel 2[AFR0]
30	25	PD0/ TIM1_BKIN [CLK_CCO]	I/O	**X**	X	X	HS	O3	X	X	Port D0	Timer 1 - break input	Configurable clock output [AFR5]
31	26	PD1/ SWIM(4)	I/O	**X**	X	X	HS	O4	X	X	Port D1	SWIM data interface	-
32	27	PD2/AIN3/ [TIM5_CH3]	I/O	**X**	X	X	HS	O3	X	X	Port D2	-	Analog input 3 [AFR2] Timer 5 - channel 3 [AFR1]
1	28	PD3/ AIN4/ TIM5_CH2/ ADC_ETR	I/O	**X**	X	X	HS	O3	X	X	Port D3	Analog input 4 Timer 5 - channel 2/ADC external trigger	-
2	29	PD4/ TIM5_CH1/ BEEP [UART1_CK]	I/O	**X**	X	X	HS	O3	X	X	Port D4	Timer 5 - channel 1/BEEP output	UART clock [AFR2]
3	30	PD5/ AIN5/ UART1_TX	I/O	**X**	X	X	HS	O3	X	X	Port D5	Analog input 5/ UART1 data transmit	-

Table 8. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5250	TIM1	TIM1_CR1	TIM1 control register 1	0x00
0x00 5251		TIM1_CR2	TIM1 control register 2	0x00
0x00 5252		TIM1_SMCR	TIM1 slave mode control register	0x00
0x00 5253		TIM1_ETR	TIM1 external trigger register	0x00
0x00 5254		TIM1_IER	TIM1 interrupt enable register	0x00
0x00 5255		TIM1_SR1	TIM1 status register 1	0x00
0x00 5256		TIM1_SR2	TIM1 status register 2	0x00
0x00 5257		TIM1_EGR	TIM1 event generation register	0x00
0x00 5258		TIM1_CCMR1	TIM1 capture/compare mode register 1	0x00
0x00 5259		TIM1_CCMR2	TIM1 capture/compare mode register 2	0x00
0x00 525A		TIM1_CCMR3	TIM1 capture/compare mode register 3	0x00
0x00 525B		TIM1_CCMR4	TIM1 capture/compare mode register 4	0x00
0x00 525C		TIM1_CCER1	TIM1 capture/compare enable register 1	0x00
0x00 525D		TIM1_CCER2	TIM1 capture/compare enable register 2	0x00
0x00 525E		TIM1_CNTRH	TIM1 counter high	0x00
0x00 525F		TIM1_CNTRL	TIM1 counter low	0x00
0x00 5260		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 5261		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 5262		TIM1_ARRH	TIM1 auto-reload register high	0xFF
0x00 5263		TIM1_ARRL	TIM1 auto-reload register low	0xFF
0x00 5264		TIM1_RCR	TIM1 repetition counter register	0x00
0x00 5265		TIM1_CCR1H	TIM1 capture/compare register 1 high	0x00
0x00 5266		TIM1_CCR1L	TIM1 capture/compare register 1 low	0x00
0x00 5267		TIM1_CCR2H	TIM1 capture/compare register 2 high	0x00
0x00 5268		TIM1_CCR2L	TIM1 capture/compare register 2 low	0x00
0x00 5269		TIM1_CCR3H	TIM1 capture/compare register 3 high	0x00

Table 8. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5300	TIM5	TIM5_CR1	TIM5 control register 1	0x00
0x00 5301		TIM5_CR2	TIM5 control register 2	0x00
0x00 5302		TIM5_SMCR	TIM5 slave mode control register	0x00
0x00 5303		TIM5_IER	TIM5 Interrupt enable register	0x00
0x00 5304		TIM5_SR1	TIM5 status register 1	0x00
0x00 5305		TIM5_SR2	TIM5 status register 2	0x00
0x00 5306		TIM5_EGR	TIM5 event generation register	0x00
0x00 5307		TIM5_CCMR1	TIM5 capture/compare mode register 1	0x00
0x00 5308		TIM5_CCMR2	TIM5 capture/compare mode register 2	0x00
0x00 5309		TIM5_CCMR3	TIM5 capture/compare mode register 3	0x00
0x00 530A		TIM5_CCER1	TIM5 capture/compare enable register 1	0x00
0x00 530B		TIM5_CCER2	TIM5 capture/compare enable register 2	0x00
0x00 530C		TIM5_CNTRH	TIM5 counter high	0x00
0x00 530D		TIM5_CNTRL	TIM5 counter low	0x00
0x00 530E		TIM5_PSCR	TIM5 prescaler register	0x00
0x00 530F		TIM5_ARRH	TIM5 auto-reload register high	0xFF
0x00 5310		TIM5_ARRL	TIM5 auto-reload register low	0xFF
0x00 5311		TIM5_CCR1H	TIM5 capture/compare register 1 high	0x00
0x00 5312		TIM5_CCR1L	TIM5 capture/compare register 1 low	0x00
0x00 5313		TIM5_CCR2H	TIM5 capture/compare reg. 2 high	0x00
0x00 5314		TIM5_CCR2L	TIM5 capture/compare register 2 low	0x00
0x00 5315		TIM5_CCR3H	TIM5 capture/compare register 3 high	0x00
0x00 5316		TIM5_CCR3L	TIM5 capture/compare register 3 low	0x00
0x00 5317 to 0x00 533F	Reserved area (43 byte)			

6.2.3 CPU/SWIM/debug module/interrupt controller registers

Table 9. CPU/SWIM/debug module/interrupt controller registers

Address	Block	Register label	Register name	Reset status
0x00 7F00	CPU(1)	A	Accumulator	0x00
0x00 7F01		PCE	Program counter extended	0x00
0x00 7F02		PCH	Program counter high	0x00
0x00 7F03		PCL	Program counter low	0x00
0x00 7F04		XH	X index register high	0x00
0x00 7F05		XL	X index register low	0x00
0x00 7F06		YH	Y index register high	0x00
0x00 7F07		YL	Y index register low	0x00
0x00 7F08		SPH	Stack pointer high	0x03
0x00 7F09		SPL	Stack pointer low	0xFF
0x00 7F0A		CCR	Condition code register	0x28
0x00 7F0B to 0x00 7F5F	Reserved area (85 byte)			
0x00 7F60	CPU	CFG_GCR	Global configuration register	0x00
0x00 7F70	ITC	ITC_SPR1	Interrupt software priority register 1	0xFF
0x00 7F71		ITC_SPR2	Interrupt software priority register 2	0xFF
0x00 7F72		ITC_SPR3	Interrupt software priority register 3	0xFF
0x00 7F73		ITC_SPR4	Interrupt software priority register 4	0xFF
0x00 7F74		ITC_SPR5	Interrupt software priority register 5	0xFF
0x00 7F75		ITC_SPR6	Interrupt software priority register 6	0xFF
0x00 7F76		ITC_SPR7	Interrupt software priority register 7	0xFF
0x00 7F77		ITC_SPR8	Interrupt software priority register 8	0xFF
0x00 7F78 to 0x00 7F79	Reserved area (2 byte)			
0x00 7F80	SWIM	SWIM_CSR	SWIM control status register	0x00
0x00 7F81 to 0x00 7F8F	Reserved area (15 byte)			

Table 9. CPU/SWIM/debug module/interrupt controller registers (continued)

Address	Block	Register label	Register name	Reset status
0x00 7F90	DM	DM_BK1RE	DM breakpoint 1 register extended byte	0xFF
0x00 7F91		DM_BK1RH	DM breakpoint 1 register high byte	0xFF
0x00 7F92		DM_BK1RL	DM breakpoint 1 register low byte	0xFF
0x00 7F93		DM_BK2RE	DM breakpoint 2 register extended byte	0xFF
0x00 7F94		DM_BK2RH	DM breakpoint 2 register high byte	0xFF
0x00 7F95		DM_BK2RL	DM breakpoint 2 register low byte	0xFF
0x00 7F96		DM_CR1	DM debug module control register 1	0x00
0x00 7F97		DM_CR2	DM debug module control register 2	0x00
0x00 7F98		DM_CSR1	DM debug module control/status register 1	0x10
0x00 7F99		DM_CSR2	DM debug module control/status register 2	0x00
0x00 7F9A		DM_ENFCTR	DM enable function register	0xFF
0x00 7F9B to 0x00 7F9F	Reserved area (5 byte)			

1. Accessible by debug module only.

10 Electrical characteristics

10.1 Parameter conditions

Unless otherwise specified, all voltages are referred to V_{SS}.

10.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at T_A = 25 °C, and T_A = T_{Amax} (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean ± 3 Σ).

10.1.2 Typical values

Unless otherwise specified, typical data are based on T_A = 25 °C, V_{DD} = 5.0 V. They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean ± 2 Σ).

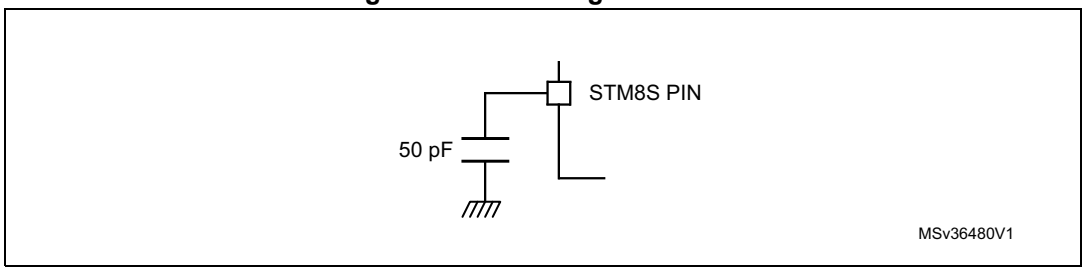
10.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

10.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 8*.

Figure 8. Pin loading conditions



10.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in *Figure 9*.

Total current consumption in wait mode

Table 25. Total current consumption in wait mode at V_{DD} = 5 V

Symbol	Parameter	Conditions		Typ	Max(1)	Unit
$I_{DD(WFI)}$	Supply current in wait mode	$f_{CPU} = f_{MASTER}$ = 16 MHz	HSE crystal osc. (16 MHz)	1.6	-	mA
			HSE user ext. clock (16 MHz)	1.1	1.3	
			HSI RC osc. (16 MHz)	0.89	1.1	
		$f_{CPU} = f_{MASTER}$ /128 = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.88	
		$f_{CPU} = f_{MASTER}$ /s128 = 15.625 kHz	HSI RC osc. (16 MHz/8)(2)	0.45	0.57	
		$f_{CPU} = f_{MASTER}$ = 128 kHz	LSI RC osc. (128 kHz)	0.4	0.54	

1. Guaranteed by characterization results.
2. Default clock configuration measured with all peripherals off.

Table 26. Total current consumption in wait mode at V_{DD} = 3.3 V

Symbol	Parameter	Conditions		Typ	Max(1)	Unit
$I_{DD(WFI)}$	Supply current in wait mode	$f_{CPU} = f_{MASTER}$ = 16 MHz	HSE crystal osc. (16 MHz)	1.1	-	mA
			HSE user ext. clock (16 MHz)	1.1	1.3	
			HSI RC osc. (16 MHz)	0.89	1.1	
		$f_{CPU} = f_{MASTER}$ /128 = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.88	
		$f_{CPU} = f_{MASTER}$ /s128 = 15.625 kHz	HSI RC osc. (16 MHz/8)(2)	0.45	0.57	
		$f_{CPU} = f_{MASTER}$ = 128 kHz	LSI RC osc. (128 kHz)	0.4	0.54	

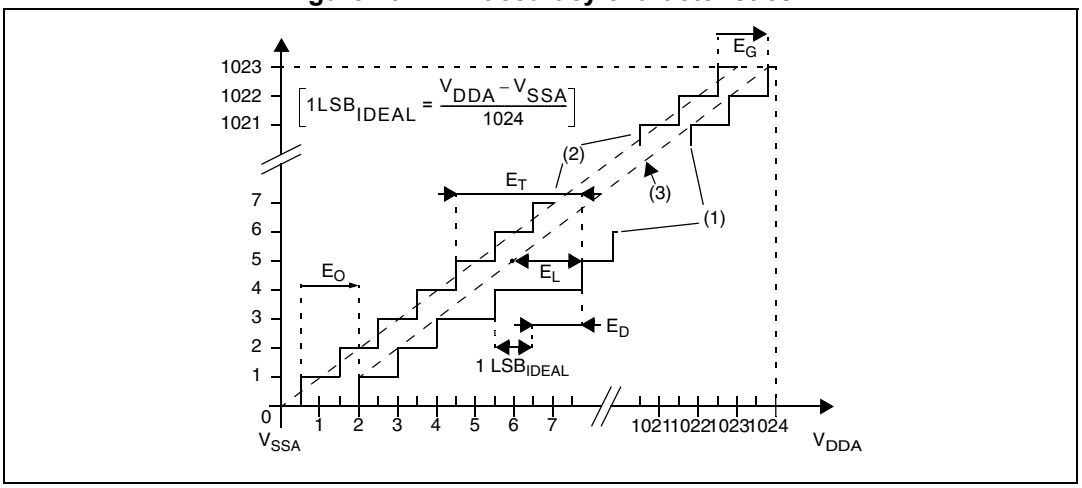
1. Guaranteed by characterization results.
2. Default clock configuration measured with all peripherals off.

Table 49. ADC accuracy with R_{AIN}< 10 kΩ, V_{DD}= 3.3 V

Symbol	Parameter	Conditions	Typ	Max(1)	Unit
$\|E_T\|$	Total unadjusted error(2)	f_{ADC} = 2 MHz	1.6	3.5	LSB
		f_{ADC} = 4 MHz	1.9	4	
$\|E_O\|$	Offset error(2)	f_{ADC} = 2 MHz	1	2.5	
		f_{ADC} = 4 MHz	1.5	2.5	
$\|E_G\|$	Gain error(2)	f_{ADC} = 2 MHz	1.3	3	
		f_{ADC} = 4 MHz	2	3	
$\|E_D\|$	Differential linearity error(2)	f_{ADC} = 2 MHz	0.7	1.0	
		f_{ADC} = 4 MHz	0.7	1.5	
$\|E_L\|$	Integral linearity error(2)	f_{ADC} = 2 MHz	0.6	1.5	
		f_{ADC} = 4 MHz	0.8	2	

1. Guaranteed by characterization results.
2. ADC accuracy vs. negative injection current: Injecting negative current on any of the analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current. Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 10.3.6* does not affect the ADC accuracy.

Figure 43. ADC accuracy characteristics



1. Example of an actual transfer curve
2. The ideal transfer curve
3. End point correlation line
   E_T = Total unadjusted error: maximum deviation between the actual and the ideal transfer curves.
   E_O = Offset error: deviation between the first actual transition and the first ideal one.
   E_G = Gain error: deviation between the last ideal transition and the last actual one.
   E_D = Differential linearity error: maximum deviation between actual steps and the ideal one.
   E_L = Integral linearity error: maximum deviation between any actual transition and the end point correlation line.

10.3.11 EMC characteristics

Susceptibility tests are performed on a sample basis during product characterization.

Functional EMS (electromagnetic susceptibility)

While executing a simple application (toggling 2 LEDs through I/O ports), the product is stressed by two electromagnetic events until a failure occurs (indicated by the LEDs).

- **ESD**: Electrostatic discharge (positive and negative) is applied on all pins of the device until a functional disturbance occurs. This test conforms with the IEC 61000-4-2 standard.
- **FTB**: A burst of fast transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test conforms with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed. The test results are given in the table below based on the EMS levels and classes defined in application note AN1709 (EMC design guide for STM microcontrollers).

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be recovered by applying a low state on the NRST pin or the oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring. See application note AN1015 (Software techniques for improving microcontroller EMC performance).

Table 50. EMS data

Symbol	Parameter	Conditions	Level/class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, T_A= 25 °C, f_{MASTER} = 16 MHz (HSI clock), Conforms to IEC 61000-4-2	2/B(1)
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD} = 3.3 V, T_A= 25 °C, f_{MASTER} = 16 MHz (HSI clock), Conforms to IEC 61000-4-4	4/A(1)

1. Data obtained with HSI clock configuration, after applying the hardware recommendations described in AN2860 (EMC guidelines for STM8S microcontrollers).

Electromagnetic interference (EMI)

Based on a simple application running on the product (toggling 2 LEDs through the I/O ports), the product is monitored in terms of emission. This emission test is in line with the norm IEC 61967-2 which specifies the board and the loading of each pin.

Table 51. EMI data

Symbol	Parameter	Conditions				Unit
		General conditions	Monitored frequency band	Max f_{CPU}(1)		
				16 MHz/ 8 MHz	16 MHz/ 16 MHz	
S_{EMI}	Peak level	V_{DD} = 5 V, T_A = 25 °C, LQFP32 package. Conforming to IEC 61967-2	0.1 MHz to 30 MHz	5	5	dBµV
			30 MHz to 130 MHz	4	5	
			130 MHz to 1 GHz	5	5	
	EMI level		EMI level	2.5	2.5	-

1. Guaranteed by characterization results.

Absolute maximum ratings (electrical sensitivity)

Based on two different tests (ESD, DLU and LU) using specific measurement methods, the product is stressed to determine its performance in terms of electrical sensitivity. For more details, refer to the application note AN1181.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts x (n+1) supply pin). One model can be simulated: Human body model. This test conforms to the JESD22-A114A/A115A standard. For more details, refer to the application note AN1181.

Table 52. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value(1)	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (Human body model)	T_A = 25°C, conforming to JESD22-A114	A	4000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (Charge device model)	T_A= 25°C, conforming to SD22-C101 LQFP32 package	IV	1000	

1. Guaranteed by characterization results

Static latch-up

Two complementary static tests are required on 10 parts to assess the latch-up performance.

- A supply overvoltage (applied to each power supply pin), and
- A current injection (applied to each input, output and configurable I/O pin) are performed on each sample.

11.5 TSSOP20 package information

Figure 56. TSSOP20 package outline

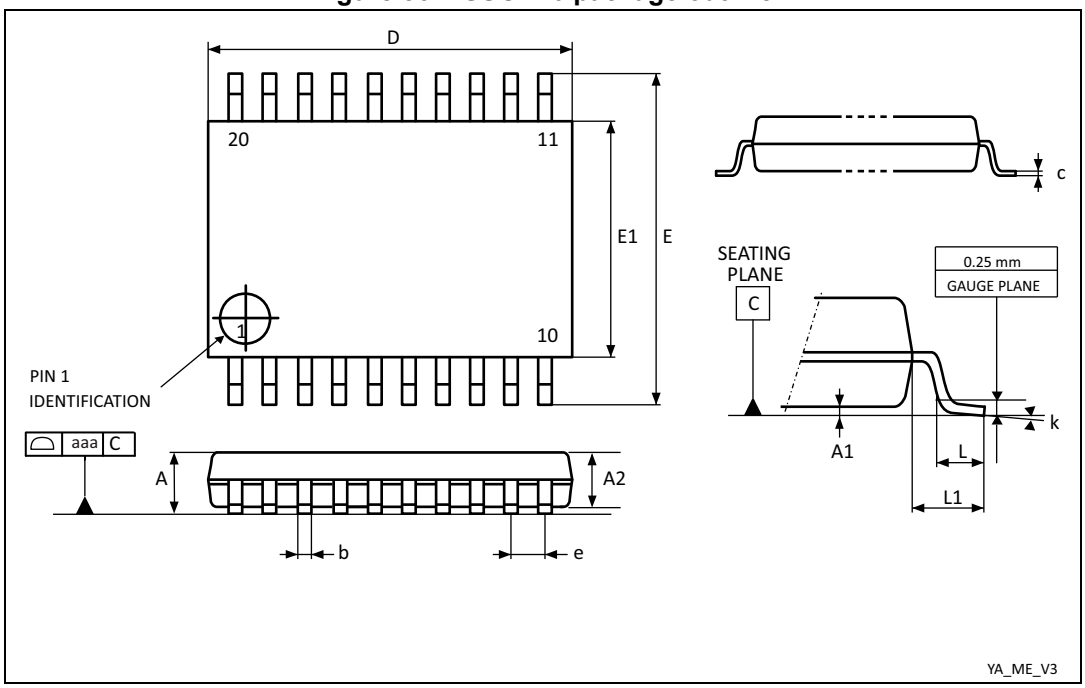


Table 58. TSSOP20 package mechanical data

Dim.	mm			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.200	-	-	0.0472
A1	0.050	-	0.150	0.0020	-	0.0059
A2	0.800	1.000	1.050	0.0315	0.0394	0.0413
b	0.190	-	0.300	0.0075	-	0.0118
c	0.090	-	0.200	0.0035	-	0.0079
D[2]	6.400	6.500	6.600	0.2520	0.2559	0.2598
E	6.200	6.400	6.600	0.2441	0.2520	0.2598
E1[3]	4.300	4.400	4.500	0.1693	0.1732	0.1772
e	-	0.650	-	-	0.0256	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0.0°	-	8.0°	0.0°	-	8.0°
aaa	-	-	0.100	-	-	0.0039

1. Values in inches are converted from mm and rounded to 4 decimal digits.
2. Dimension “D” does not include mold flash, protrusions or gate burrs. Mold flash, protrusions or gate burrs shall not exceed 0.15mm per side.

11.6 SO20 package information

Figure 59. SO20 package outline

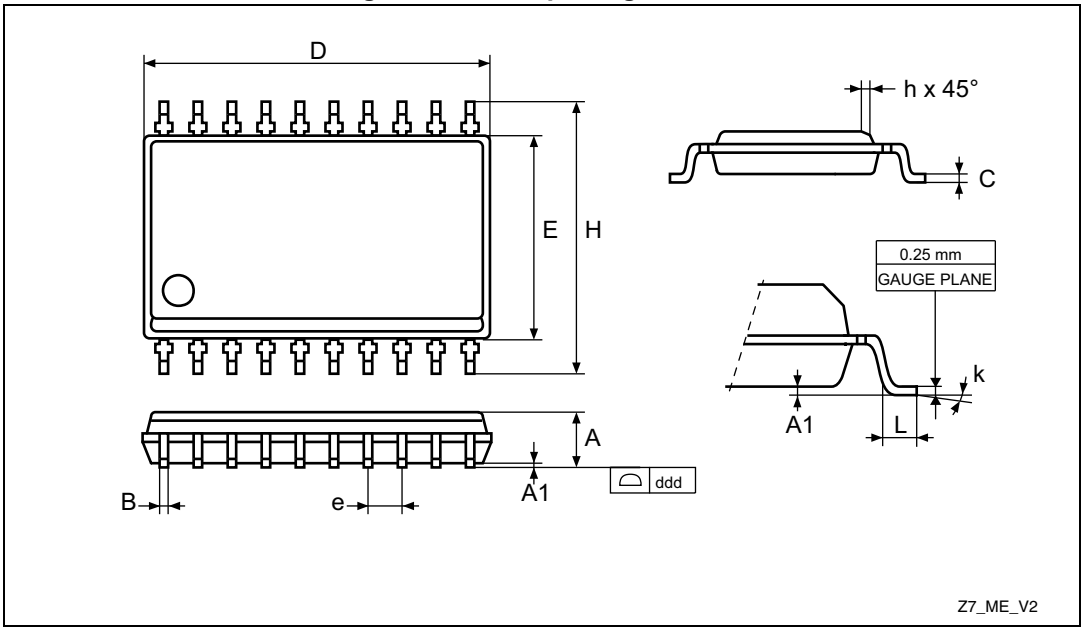


Table 59. SO20 mechanical data

Dim.	mm			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	2.350	-	2.650	0.0925	-	0.1043
A1	0.100	-	0.300	0.0039	-	0.0118
B	0.330	-	0.510	0.013	-	0.0201
C	0.230	-	0.320	0.0091	-	0.0126
D	12.600	-	13.000	0.4961	-	0.5118
E	7.400	-	7.600	0.2913	-	0.2992
e	-	1.270	-	-	0.0500	-
H	10.000	-	10.650	0.3937	-	0.4193
h	0.250	-	0.750	0.0098	-	0.0295
L	0.400	-	1.270	0.0157	-	0.0500
k	0.0°	-	8.0°	0.0°	-	8.0°
ddd	-	-	0.100	-	-	0.0039

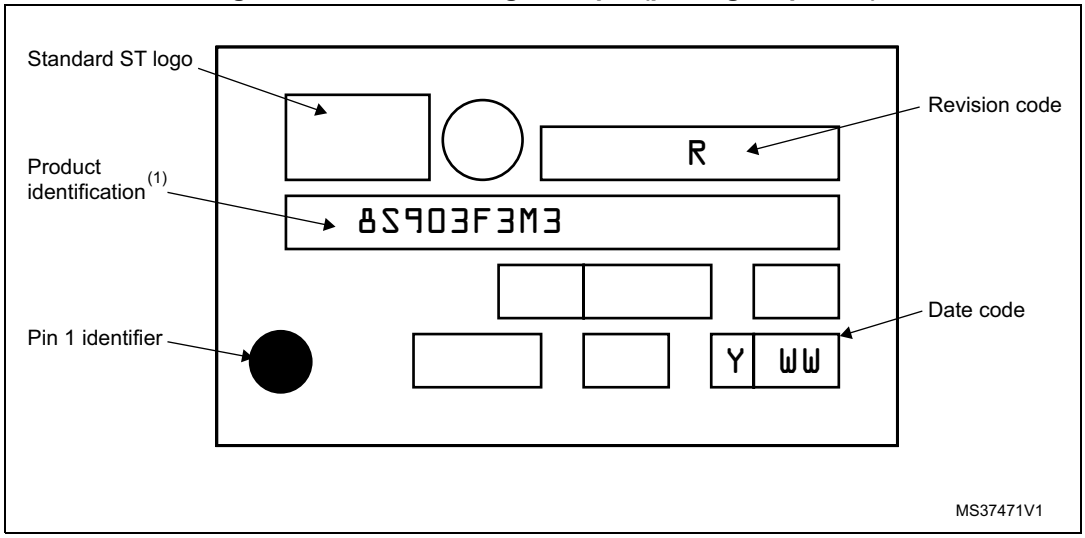
1. Values in inches are converted from mm and rounded to 4 decimal digits.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

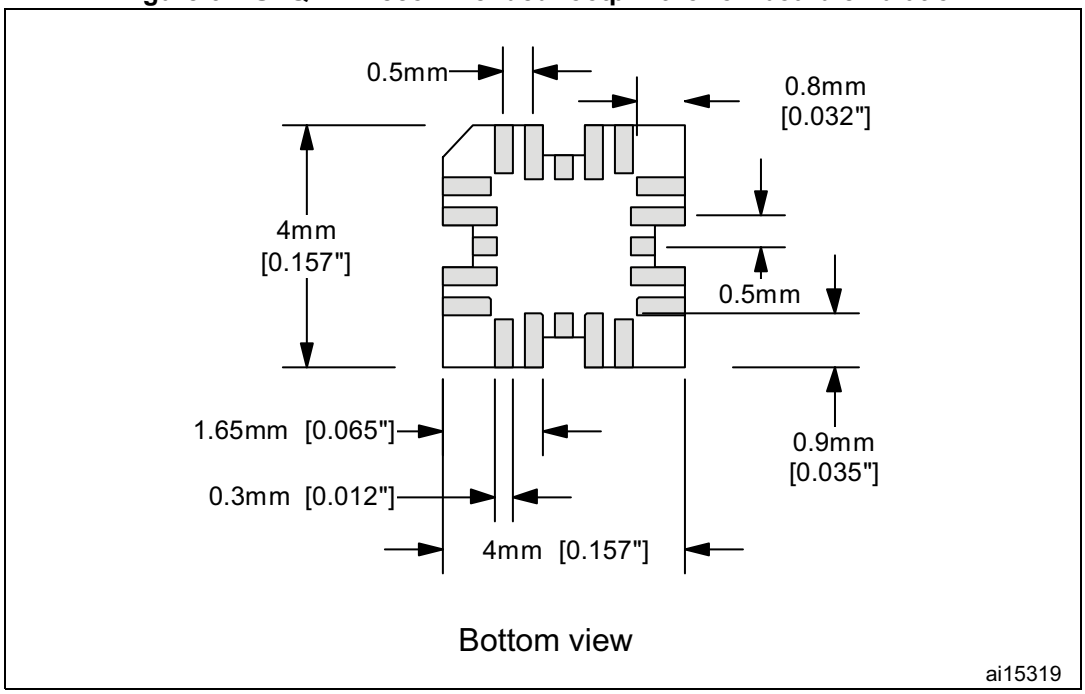
Figure 60. SO20 marking example (package top view)



1. Parts marked as “ES”,”E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

11.7 UFQFPN recommended footprint

Figure 61. UFQFPN recommended footprint for on-board emulation



12.2 Selecting the product temperature range

When ordering the microcontroller, the temperature range is specified in the order code (see *Section 13: Ordering information*).

The following example shows how to calculate the temperature range needed for a given application.

Assuming the following application conditions:

Maximum ambient temperature T_{Amax}= 75°C (measured according to JESD51-2), I_{DDmax} = 8 mA, V_{DD} = 5 V, maximum 20 I/Os used at the same time in output at low level with

I_{OL} = 8 mA, V_{OL}= 0.4 V

P_{INTmax} = 8 mA x 5 V= 400 mW

P_{IOmax} = 20 x 8 mA x 0.4 V = 64 mW

This gives: P_{INTmax} = 400 mW and P_{IOmax} 64 mW:

P_{Dmax} = 400 mW + 64 mW

Thus: P_{Dmax} = 464 mW.

Using the values obtained in *Table 60: Thermal characteristics on page 107* T_{Jmax} is calculated as follows:

For LQFP32 60 °C/W

T_{Jmax} = 75 °C + (60 °C/W x 464 mW) = 75 °C + 27.8 °C = 102.8 °C

This is within the range of the suffix 6 version parts (-40 < T_J < 105 °C).

Parts must be ordered at least with the temperature range suffix 6.

Table 61. Document revision history (continued)

Date	Revision	Changes
26-Mar-2015	10	Corrected the values for “b” dimensions in *Table 55: UFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch ultra thin fine pitch quad flat package mechanical data*.
13-Feb-2017	11	Updated: – Analog to digital converter (ADC) features on *Section : Features* – *Section 10.2: Absolute maximum ratings* – *Table 5: TSSOP20/SO20/UFQFPN20 pin descriptions* – *Table 19: Current characteristics* – *Table 33: Peripheral current consumption* – *Table 47: ADC characteristics* – *Table 56: UFQFPN20 - 20-lead, 3x3 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package mechanical data* – *Figure 18: HSE external clock source* – *Figure 19: HSE oscillator circuit diagram* – *Figure 40: SPI timing diagram where slave mode and CPHA = 1* – *Figure 41: SPI timing diagram - master mode* – *Figure 44: Typical application with ADC* – *Section : Electromagnetic interference (EMI)* – All “Device marking” sections on *Section 11: Package information* – Footnotes on the tables of *Section 10: Electrical characteristics* and of *Figure 48: UFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch ultra thin fine pitch quad flat package outline* – Title of *Table 54: LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data* and *Table 56: UFQFPN20 - 20-lead, 3x3 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package mechanical data* – Title of *Figure 45: LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package outline*, *Figure 46: LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package recommended footprint*, *Figure 51: UFQFPN20 - 20-lead, 3x3 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package outline* Added: – *Figure 52: UFQFPN20 - 20-lead, 3x3 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package recommended footprint*

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